## NTEK 北测

## **EMC TEST REPORT**

ETSI EN 301 489-1 V2.2.3 (2019-11) ETSI EN 301 489-3 V2.1.1 (2019-03) ETSI EN 301 489-17 V3.2.4 (2020-09) ETSI EN 301 489-19 V2.1.1 (2019-04) ETSI EN 301 489-52 V1.2.1 (2021-11) EN 55032:2015+A1:2020 EN 55035:2017+A11:2020 EN IEC 61000-3-2:2019+A1:2021 EN 61000-3-3:2013+A2:2021

> Product : Smart phone Trade Mark : Blackview Model Name : A53 Family Model : N/A Report No. : STR221216001011E

## **Prepared for**

DOKE COMMUNICATION (HK) LIMITED

RM 1902 EASEY COMM BLDG 253-261 HENNESSY ROAD WANCHAI HK CHINA

## Prepared by

Shenzhen NTEK Testing Technology Co., Ltd.

 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen 518126 P.R. China
 Tel. 400-800-6106, 0755-2320 0050, 0755-2320 0090 Website: http://www.ntek.org.cn

## **NTEK 北测**

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## **TEST RESULT CERTIFICATION**

Applicant's Name	DOKE COMMUNICATION (HK) LIMITED
Address	RM 1902 EASEY COMM BLDG 253-261 HENNESSY ROAD WANCHAI HK CHINA
Manufacturer's Name	: Shenzhen DOKE Electronic Co.,Ltd
Address	801, Building3, 7th Industrial Zone, Yulv Community, Yutang Road, Guangming District, Shenzhen, China
Product description	
Product name	: Smart phone
Trade Mark	: Blackview
Model Name	: A53
Family Model	: N/A
	ETSI EN 301 489-1 V2.2.3 (2019-11)
	ETSI EN 301 489-3 V2.1.1 (2019-03)
	ETSI EN 301 489-17 V3.2.4 (2020-09)
Standards	: ETSI EN 301 489-19 V2.1.1 (2019-04)
	ETSI EN 301 489-52 V1.2.1 (2021-11)
	EN 55032:2015+A1:2020; EN 55035:2017+A11:2020
	EN IEC 61000-3-2:2019+A1:2021;EN 61000-3-3:2013+A2:2021

This device described above has been tested by NTEK, and the test results show that the equipment under test (EUT) is in compliance with the of article 3.1(b) of the Directive 2014/53/EU requirements. And it is applicable only to the tested sample identified in the report. This report shall not be reproduced except in full, without the written approval of NTEK, this document may be altered or revised by NTEK, personnel only, and shall be noted in the revision of the document.

Test Sample Number .....: T221216001R0030

Date of Test

Date (s) of performance of tests .....: Dec 16, 2022 ~ Jan 11, 2023

Date of Issue...... Jan 11, 2023

Test Result..... Pass

Testing Engineer

Allen. Huang (Allen Huang)

Authorized Signatory:

(Alex Li)

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<b>1. TEST SUMMARY</b>						
Test procedures acco	rding to	the technical standards:				
ETSI EN 301 489-1 V	2.2.3 (2	2019-11)				
ETSI EN 301 489-3 V	2.1.1 (2	2019-03)				
ETSI EN 301 489-17	V3.2.4	(2020-09)				
ETSI EN 301 489-19	V2.1.1	(2019-04)				
ETSI EN 301 489-52	V121	(2021-11)				- K
EN 55032.2015+41.2	020. E	S5035·2017+∆11·2020				
EN IEC 61000 2 2:20	10. EN	61000 2 2·2012 A1·2010				
EN IEC 01000-3-2.20	19, EN	EMC Emission				
Standard		Test Item		Limit	Judgmer	t Remark
* *	Cond	ucted Emission On AC And Te Port 150kHz to 30MHz	lecom	Class	BPASS	
	Dis T	sturbance Voltage at The Anter Ferminals (30MHz To 2150MHz	nna z)		N/A	×
EN 55032:2015+A1: 2020	Wanted	l signal and disturbance voltag RF output terminals (30MHz To 2150MHz)	e at the		N/A	
	1×	Radiated Emission 30MHz to 1000MHz		Class	B PASS	¢t.
		Radiated Emission 1GHz to 6GHz	A.C.	Class	B PASS	4
EN IEC 61000-3-2:2019+A1: 2021	F	Harmonic Current Emission		Class	A N/A	NOTE (1)
EN 61000-3-3:2013+A2: 2021		Voltage Fluctuations & Flicker			PASS	*
		EMC Immunity				
Section EN 55035:2017+A11	:2020	Test Item	Perforn Crite	nance eria	Judgment	Remark
EN 61000-4-2:20	09	Electrostatic Discharge	В	St.	PASS	•
EN 61000-4-3:200 A1:2008+A2:201	06+ 0	RF electromagnetic field	A		PASS	
EN 61000-4-4:20	12	Fast transients	В		PASS	4
EN 61000-4-5:201 A1:2017	4+	Surges	В		PASS	
EN 61000-4-6:20	14	Continuous radio frequency disturbances or Injected Current	А		PASS	A.C.
EN 61000-4-8:20	10	Power Frequency Magnetic Field	A		N/A	NOTE (3)
EN 61000-4-11:20	04	Volt. Interruptions Volt. Dips	В / С <b>NOTE</b>	/ C (2)	PASS	

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### NOTE:

- (1)" N/A" denotes test is not applicable in this Test Report
- (2) Voltage dip: 100% reduction Performance Criteria B
  - Voltage dip: 30% reduction Performance Criteria C
  - Voltage Interruption: 100% Interruption Performance Criteria C

(3) Applicable only to equipment containing devices intrinsically susceptible to magnetic fields, such as CRT monitors, Hall effect elements, electro-dynamic microphones, magnetic field sensors or audio frequency transformers.

(4) For client's request and manual description, the test will not be executed.

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## 1.1 TEST FACILITY

Shenzhen NTEK Testing Technology Co., Ltd. Add. : 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen 518126 P.R. China

CNAS-Lab.	: The Certificate Registration Number is L5516
IC-Registration	: The Certificate Registration Number is CN0074
FCC- Accredited	: Test Firm Registration Number: 463705
	Designation Number: CN1184
A2LA-Lab.	: The Certificate Registration Number is 4298.01
	This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories.
	This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).

## 1.2 MEASUREMENT UNCERTAINTY

The reported uncertainty of measurement  $\mathbf{y} \pm \mathbf{U}$ , where expended uncertainty  $\mathbf{U}$  is based on a standard uncertainty multiplied by a coverage factor of **k=2**, providing a level of confidence of approximately **95** %.

Test Item	Measurement Frequency Range	К	U(dB)
AC Mains Conducted Emission	0.009kHz ~ 0.15MHz	2	2.66
AC Mains Conducted Emission	0.15MH ~ 30MHz	2	2.80
Telecom Conducted Emission (Cat 3)	0.15MHz ~ 30MHz	2	2.40
Telecom Conducted Emission (Cat 5)	0.15MHz ~ 30MHz	2	2.58
Radiated Emission	30MHz ~ 1000MHz	2	2.64
Radiated Emission	1000MHz ~ 6000MHz	2	2.40
Radiated Emission	6000MHz ~ 18000MHz	2	2.52

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Report No.	Version	Description	Issued Date
STR221216001011E	Rev.01	Initial issue of report	Jan 11, 2023
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## NTEK 北测

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### 2. GENERAL INFORMATION 2.1 GENERAL DESCRIPTION OF EUT Smart phone Equipment Blackview Trade Mark Model Name A53 N/A Family Model N/A Model Difference BT: 2402~2480 MHz 2.4G WIFI: 802.11b/g/n(20MHz): 2412~2472MHz 802.11n(40MHz):2422~2462MHz ⊠5G WIFI:802.11a/ n(20/40)/ ac(20/40/80): 5180MHz~5240MHz;(20MHz) 5190MHz~5230MHz;(40MHz) 5210MHz;(80MHz) 5745-5825 MHz for 802.11a/n20/ac20; 5755-5795 MHz for 802.11n40/ac40; 5775MHz for 802.11 ac80; GSM/GPRS/EGPRS 900: 880~915MHz(TX) 925~960MHz (Rx) GSM/GPRS/EGPRS 1800: 1710~1785MHz(TX) 1805~1880MHz(Rx) WCDMA Band I: 1920 MHz ~1980 MHz(TX); 2110 MHz~2170 MHz(RX) Frequency Bands: WCDMA Band VIII: 880~915MHz(TX); 925~960MHz(RX) E-UTRA FDD Band I, III, VII, VIII, XX E-UTRA TDD XL FDD Band I: Uplink: 1920 MHz to 1980MHz Downlink: 2110 MHz to 2170 MHz FDD Band III: Uplink:1710 MHz to 1785 MHz Downlink: 1805 MHz to 1880 MHz FDD Band VII: Uplink: 2500 MHz to 2570 MHz Downlink: 2620 MHz to 2690 MHz FDD Band VIII: Uplink: 880MHz to 915 MHz Downlink: 925 MHz to 960 MHz FDD Band XX: Uplink: 832 MHz to 862 MHz Downlink: 791 MHz – 821 MHz TDD Band XL: Uplink & Downlink: 2300 MHz to 2400 MHz FM Receiver: 87.5 MHz to 108 MHz GPS: 1.57542GHz

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Modulation Mode:	<ul> <li>BT(1Mbps)/BLE: GFSK</li> <li>BT EDR(2Mbps): π/4-DQPSK</li> <li>BT EDR(3Mbps): 8-DPSK</li> <li>BLE(2Mbps): GFSK</li> <li>IEEE 802.11b : DSSS (CCK, DQPSK, DBPSK)</li> <li>IEEE 802.11g/n (HT20/HT40) : OFDM (64QAM, 16QAM, QPSK, BPSK)</li> <li>802.11a:OFDM (BPSK / QPSK / 16QAM)</li> <li>802.11n:OFDM (QPSK/BPSK/16QAM/64QAM)</li> <li>802.11ac:OFDM (QPSK/BPSK/16QAM/64QAM)</li> <li>802.11ac:OFDM (QPSK/BPSK/16QAM/64QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/16QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/16QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/16QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/16QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/16QAM/64QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/BPSK/16QAM/64QAM/64QAM/256QAM)</li> <li>S02.11ac:OFDM (QPSK/BPSK/BPSK/BPSK)</li> </ul>
Adapter	Model: QZ-01000EA00 Input: 100-240V~50/60Hz 0.3A Output: 5.0V2.0A (10.0W)
Battery	DC 3.87V, 5080mAh, 19.66Wh
Rating	DC 3.87V from battery or DC 5V from adapter
Connecting I/O Port(s)	Please refer to the User's Manual
Antenna:	BT/WIFI/GPS: PIFA Antenna; GSM/WCDMA/LTE: PIFA Antenna; FM: Use earphone as Antenna;
Hard Ware Version	HCT-M659MB-A2
Soft Ware Version	A53_EEA_M659_V1.0

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## 2.2 DESCRIPTION OF TEST MODES

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Pretest Mode	Description
Mode 1	Charging + REC(Rear / Front)
Mode 2	Charging + TF Playing
Mode 3	Data transmission
Mode 4	Charging + FM(87.6MHz / 98MHz / 107.9MHz)
Mode 5	BT Link mode
Mode 6	Wi-Fi 2.4G/ Wi-Fi 5.2G/ Wi-Fi 5.8G
Mode 7	GSM / GPRS / EGPRS 900 / 1800
Mode 8	WCDMA / HSDPA / HSUPA B1 / B8
Mode 9	LTE Band 1 / 3 / 7 / 8 / 20 / 40
Mode 10	GPS Receiver

For Conducted Test		
Final Test Mode	Description	
Mode 2	Charging + TF Playing	



	For Radiated Test
Final Test Mode	Description
Mode 2	Charging + TF Playing
A 2	
	For EMS Test
Pretest Mode	Description
Mode 1	Charging + REC(Rear / Front)
Mode 2	Charging + TF Playing
Mode 3	Data transmission
Mode 4	Charging + FM(87.6MHz / 98MHz / 107.9MHz)
Mode 5	BT Link mode
Mode 6	Wi-Fi 2.4G/ Wi-Fi 5.2G/ Wi-Fi 5.8G
Mode 7	GSM / GPRS / EGPRS 900 / 1800
Mode 8	WCDMA / HSDPA / HSUPA B1 / B8
Mode 9	LTE Band 1 / 3 / 7 / 8 / 20 / 40
Mode 10	GPS Receiver

NOTE: The test modes were carried out for all operation modes. The final test mode of the EUT was the worst test mode for EMI, and its test data was showed.

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## 2.4 DESCRIPTION TEST PERIPHERAL AND EUT PERIPHERAL

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Model/Type No.	Series No.	Note
E-1	Smart phone	A53	N/A	EUT
E-2	Adapter	QZ-01000EA00	N/A	Peripherals
E-3	Earphone	N/A	N/A	Peripherals
			X	~ ~
	2	×		

			•		
Item	Cable Type	Shielded Type	Ferrite Core	Length	Note
C-1	USB Cable	NO	NO	🤍 1.0m 🤝	4
C-1	Earphone Cable	NO	NO	1.2m	
			7		

Note:

(2)

- (1) The support equipment was authorized by Declaration of Confirmation.
  - For detachable type I/O cable should be specified the length in cm in [Length] column.

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## 2.5 MEASUREMENT INSTRUMENTS LIST

## 2.5.1CONDUCTED EMISSION

	ltem	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
	4	Test Cable	N/A	C01	N/A	Mar. 29, 2021	Mar. 28, 2024	3 years
	2	Test Cable	N/A	C02	N/A	Mar. 29, 2021	Mar. 28, 2024	3 years
	3	Test Cable	N/A	C03	N/A	Mar. 29, 2021	Mar. 28, 2024	3 years
	4	Pulse Limiter	SCHWARZBE CK	VTSD 9561F	9716	Apr .06, 2022	Apr .05, 2023	1 year
	5	50Ω Switch	ANRITSU CORP	MP59B	620098370 4	May. 11, 2021	May. 10, 2024	3 year
	6	EMI Test Receiver	R&S	ESCI	101160	Apr .06, 2022	Apr .05, 2023	1 year
	7	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Apr .06, 2022	Apr .05, 2023	1 year
	8	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Apr .06, 2022	Apr .05, 2023	1 year
	9	LISN	SCHWARZBE CK	NNLK 8129	8129245	Apr .06, 2022	Apr .05, 2023	1 year
	10	LISN	R&S	ENV216	101313	Apr .06, 2022	Apr .05, 2023	1 year
с 2	52							
[	Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
	1	Antenna Mast	EM	SC100_1	N/A	N/A	N/A	N/A
	2	Turn Table	EM	SC100	060531	N/A	N/A	N/A
	3	EMI Test Receiver	R&S	ESCI-7	101318	Apr .06, 2022	Apr .05, 2023	1 year
	4	50Ω Switch	Anritsu Corp	MP59B	620098370 5	May. 11, 2021	May. 10, 2024	3 year
	5	Spectrum Analyzer	Aglient	E4407B	MY451080 40	Apr .01, 2022	Mar .31 2023	1 year
	6	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun.16, 2022	Jun.15, 2023	1 year
	7	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun.16, 2022	Jun.15, 2023	1 year
	8	Test Cable	N/A	R-01	N/A	Jun. 17, 2022	Jun. 16, 2025	3 years
ļ	9	Test Cable	N/A	R-02	<₽N/A	Jun. 17, 2022	Jun. 16, 2025	3 years
ĺ	10	Bilog Antenna	TESEQ	CBL6111D	31216	Mar. 30, 2022	Mar. 29, 2023	1 year
	11	Horn Antenna	ЕМ	EM-AH-101 80	201107140 2	Mar. 31, 2022	Mar. 30, 2023	1 year
	12	Amplifier	EMC	EMC05183 5SE	980246	Apr .01, 2022	Mar .31 2023	1 year

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2.5.3	HARMONICS A	ND FILCK					
Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
1	Harmonic & Flicker	EM TEST	DPA500	0303-04	Apr .06, 2022	Apr .05, 2023	1 year
2	AC Power Source	EM TEST	ACS500	0203-01	Apr .06, 2022	Apr .05, 2023	1 year
3	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun. 16, 2022	Jun. 15, 2023	1 year
4	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun. 16, 2022	Jun. 15, 2023	1 year
254	ESD						
Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
1	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun. 16, 2022	Jun. 15, 2023	1 year
2	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun. 16, 2022	Jun. 15, 2023	1 year
3	Electrostatic Discharge Generator	Lioncel	ESD-203B	ESD203B0 150402	Jun. 16, 2022	Jun. 15, 2023	1 year
255	RS (	~ ~		·		¥	
Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
1	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun. 16, 2022	Jun. 15, 2023	1 year
2	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun. 16, 2022	Jun. 15, 2023	1 year
3	Audio Power Amplifier	Brüel & Kjær	4602B	2185667	Apr .06, 2022	Apr .05, 2023	1 year
4	Mouth Simulator	Brüel & Kjær	2669	2143265	Apr .06, 2022	Apr .05, 2023	1 year
5	Sound Calibrator	Brüel & Kjær	4185	2194825	Apr .06, 2022	Apr .05, 2023	1 year
6	1/2" Pressure- field Microphone	Brüel & Kjær	735	2641678	Apr .06, 2022	Apr .05, 2023	1 year
7	Telephone Test Head	Brüel & Kjær	4185	2631728	Apr .06, 2022	Apr .05, 2023	1 year
8	Audio Analyzer	R&S	UPV	100419	Apr .06, 2022	Apr .05, 2023	1 year

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9	Ear Simulator for Telephonometr y	Brüel & Kjær	4185	2553612	Apr .06, 2022	Apr .05, 2023	1 year
10	Bilog Antenna	ETS	3142E(Fequ ency range 30MHz to 6 GHz)	00214344	Mar. 30, 2022	Jun. 29, 2023	1 year
11	Broadband Amplifier	AR	60S1G6	0350414	Jun. 26, 2022	Jun. 25, 2023	1 year
12	MXG Vector Signal Generator	Agilent	N5182A	MY470703 17	Jun. 16, 2022	Jun. 15, 2023	1 year
13	Power Amplifier	rflight	NTWPA-00 810200	17063153	Jun. 17, 2022	Jun. 16, 2023	1 year
14	Power Amplifier	AR	25S1G4A	308598	Jun. 17, 2022	Jun. 16, 2023	1 year
15	Power Meter	Agilent	E4419B	MY451025 38	Jun. 17, 2022	Jun. 16, 2023	1 year
16	Power Sensor	Agilent	E9301A	MY414956 44	Jun. 17, 2022	Jun. 16, 2023	1 year
17	Power Sensor	Agilent	E9301A	US392121 48	Jun. 17, 2022	Jun. 16, 2023	1 year

## 2.5.6 SURGE, EFT/BURST, VOLTAGE INTERRUPTION/DIPS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
1	Surge Generator	EVERFINE	EMS61000- 5A-V1	1101002	Apr .06, 2022	Apr .05, 2023	1 year
2	DIPS Generator 🏑	EVERFINE	EMS61000- 11K	1011002	Apr .06, 2022	Apr .05, 2023	1 year
3	EFT/B Generator	EVERFINE	EMS61000- 4A-V2	1012005	Apr .06, 2022	Apr .05, 2023	1 year
4	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun. 16, 2022	Jun. 15, 2023	1 year
5	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun. 16, 2022	Jun. 15, 2023	1 year

## 2.5.7 INJECTION CURRENT

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Last calibration	Calibrated until	Calibration period
1	Attenuator	TESEQ	ATN 6075	38411	N/A	N/A	N/A
2	RF Cable	TESEQ	RF Cable	N/A	N/A	N/A	N/A
3	Signal Generator	R&S	SML03	100954	Nov. 01, 2022	Oct. 31, 2023	1 year
4	Power Amplifier	TESEQ	CBA 230M-080	T44376	Jun. 16, 2022	Jun. 15, 2023	1 year
5	EM Clamp	FCC	F-203I-23M M	504	Apr .06, 2022	Apr .05, 2023	1 year
6	Audio Power Amplifier	Brüel & Kjær	4602B	2185667	Apr .06, 2022	Apr .05, 2023	1 year

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7	Mouth Simulator	Brüel & Kjær	2669	2143265	Apr .06, 2022	Apr .05, 2023	1 year
8	Sound Calibrator	Brüel & Kjær	4185	2194825	Apr .06, 2022	Apr .05, 2023	1 year
9	1/2" Pressure- field Microphone	Brüel & Kjær	735	2641678	Apr .06, 2022	Apr .05, 2023	1 year
10	Audio Analyzer	R&S	UPV	100419	Apr .06, 2022	Apr .05, 2023	1 year
11	Ear Simulator for Telephonometr y	Brüel & Kjær	4185	2553612	Apr .06, 2022	Apr .05, 2023	1 year
12	Telephone Test Head	Brüel & Kjær	4185	2631728	Apr .06, 2022	Apr .05, 2023	1 year
13	Unversal radio communication tester	R&S	CMU200	1100.008.0 2	Jun .16, 2022	Jun .15, 2023	1 year
14	Wideband Radio Communication Tester Specifications	R&S	CMW500	148500	Jun .16, 2022	Jun .15, 2023	1 year
15	Coupling and Decoupling Network	TESEQ	CDN M016	38722	Apr .06, 2022	Apr .05, 2023	1 year

## **3. EMC EMISSION TEST**

### 3.1 CONDUCTED EMISSION MEASUREMENT 3.1.1 POWER LINE CONDUCTED EMISSION

(Frequency Range 150kHz-30MHz)

 
 Table A.8 – Requirements for conducted emissions from the AC mains power ports of Class A equipment

Applicabl	e to			
1. AC mai	ns power ports (3.1.1)			
Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class A limits dB(µV)
A8.1	0,15 - 0,5	A.M.N.I	Ouesi Desk / 0 kHz	79
	0,5 - 30	Alvin		73
A8.2	0,15 - 0,5	AMN		66
	0,5 - 30	Alvin	Average / 5 kHz	60
A	1			

Apply A8.1 and A8.2 across the entire frequency range.

## Table A.9 – Requirements for conducted emissions from the AC mains power portsof Class B equipment

Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class Β limits dB(μV)
A9.1	0,15 – 0,5			66 – 56
	0,5 – 5	AMN	Quasi Peak / 9 kHz	56
	5 – 30		-	60
A9.2	0,15 - 0,5			56 – 46
_	0,5 – 5	AMN	Average / 9 kHz	46
	5 – 30			50

Apply A9.1 and A9.2 across the entire frequency range.

#### Note:

Applicable to

- (1) The tighter limit applies at the band edges.
- (2) The limit of " \* " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.

## 3.1.2 TELECOMMUNICATION PORT CONDUCTED EMISSION(VOLTAGE LIMITS)

### (Frequency Range 150kHz-30MHz)

## Table A.10 – Requirements for asymmetric mode conducted emissions from Class A equipment

Арр	licab	le to
-----	-------	-------

wired network ports (3.1.30)
 optical fibre ports (3.1.24) with metallic shield or tension members
 antenna ports (3.1.3)

Table clause	Frequency range MHz	Coupling device (see Table A.7)	Detector type / bandwidth	Class A voltage limits dB(µV)	Class A current limits dB(μA)			
A10.1	0,15 - 0,5		Overi Beek / 0 kU	97 – 87				
	0,5 – 30	AAN	Quasi Peak / 9 kHz	87	-			
	0,15 – 0,5	6 6 N			n/a			
	0,5 – 30	AAN	Average / 9 kHz	74				
A10.2	A10.2 0,15 - 0,5 CV			97 – 87	53 – 43			
	0,5 – 30	and current probe	Quasi Peak / 9 kHz	87	43			
	0,15 – 0,5	CVP		84 – 74	40 – 30			
	0,5 – 30	and current probe	Average / 9 kHz	74	30			
A10.3	0,15 – 0,5	Current Broke	Quesi Beek / 9 kHz		53 – 43			
	0,5 – 30 Current Probe Quasi Peak / 9 kHz		<b>n</b> /a	43				
	0,15 - 0,5			n/a	40 – 30			
0,5 – 30		Current Probe	Average / 9 KHZ		30			

The choice of coupling device and measurement procedure is defined in Annex C.

AC mains ports that also have the function of a wired network port shall meet the limits given in Table A.8.

The test shall cover the entire frequency range.

The application of the voltage and/or current limits is dependent on the measurement procedure used. Refer to Table C.1 for applicability.

Testing is required at only one EUT supply voltage and frequency.

Applicable to ports listed above and intended to connect to cables longer than 3 m.

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## Table A.12 – Requirements for conducted differential voltage emissions from Class B equipment

Applicable to

1. TV broadcast receiver tuner ports (3.1.8) with an accessible connector

2. RF modulator output ports (3.1.27)

3. FM broadcast receiver tuner ports (3.1.8) with an accessible connector

Table clause	Frequency range	Detector type/ bandwidth		Class B lim dB(μV) 75	Applicability	
	MHZ		Other	Local Oscillator Fundamental	Local Oscillator Harmonics	
A12.1	30 <b>–</b> 950		46	46	46	See a)
	950 – 2 150	For frequencies ≤1 GHz	46	54	54	
A12.2	950 – 2 150	Quasi Bask/	46	54	54	See b)
A12.3	30 – 300	120 kHz	46 54	54	50	See c)
	300 – 1 000				52	
A12.4	30 – 300	For frequencies	46	66	59	See d)
	300 – 1 000	≥1 GHz			52	
A12.5	30 – 950	Peak/ 1 MHz	46	76	46	See e)
	950 – 2 150	1 10112		n/a	54	1

a) Television receivers (analogue or digital), video recorders and PC TV broadcast receiver tuner cards working in channels between 30 MHz and 1 GHz, and digital audio receivers.

b) Tuner units (not the LNB) for satellite signal reception.

c) Frequency modulation audio receivers and PC tuner cards.

d) Frequency modulation car radios.

e) Applicable to EUTs with RF modulator output ports (for example DVD equipment, video recorders, camcorders and decoders etc.) designed to connect to TV broadcast receiver tuner ports.

Testing is required at only one EUT supply voltage and frequency.

The term 'other' refers to all emissions other than the fundamental and the harmonics of the local oscillator.

The test shall be performed with the device operating at each reception channel.

The test shall cover the entire frequency range.

### The following table is the setting of the receiver

5	
Receiver Parameters	Setting
Attenuation	10 dB
Start Frequency	0.15 MHz
Stop Frequency	30 MHz 📈 📈
IF Bandwidth	9 kHz 💉 🔶

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## 3.1.3 TEST PROCEDURE

- a. The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
- b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
- c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
- d. LISN at least 80 cm from nearest part of EUT chassis.
- e. For the actual test configuration, please refer to the related Item -EUT Test Photos.

## Vertical Reference Ground Plane EUT B0cm ISH Horizontal Reference Ground Plane Horizontal Reference Ground Plane

## Note: 1.Support units were connected to second LISN. 2.Both of LISNs (AMN) are 80 cm from EUT and at least 80 from other units and other metal planes

## 3.1.5 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of 2.2 Unless otherwise a special operating condition is specified in the follows during the testing.

## 3.1.4 TEST SETUP

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## 3.1.6 TEST RESULTS

EUT:	Smart phone		Model Nam	ie:	A53		
Temperature:	<b>24.7</b> ℃	24.7℃			53%		
Pressure:	1010hPa 🧷	Phase:					
Test Voltage:	DC 5V from Adap AC 230V/50Hz	oter	Test Mode:		Mode 2		
			* 5	~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~	· ·		
Frequency	Meter Reading	Factor	Emission Level	Limit	s Margin	Bomark	
(MHz)	(dBµV)	(dB)	(dBµV)	(dBµ∖	/) (dB)	nemark	
0.1980	37.37	9.61	46.98	63.69	9 -16.71	QP	
0.1980	15.44	9.61	25.05	53.69	9 -28.64	AVG	
0.6100	42.53	9.67	52.20	56.00	) -3.80	QP	
0.6100	29.94	9.67	39.61	46.00	) -6.39	AVG	
1.2579	35.83	9.68	45.51	56.00	) -10.49	<b>Q</b> P	
1.2579	20.97	9.68	30.65	46.00	) -15.35	AVG	
2.5579	34.66	9.72	44.38	56.00	) -11.62	QP	
2.5579	17.62	9.72	27.34	46.00	-18.66	AVG	
5.2740	33.44	9.78	43.22	60.00	) <-16.78	QP	
5.2740	17.80	9.78	27.58	50.00	) -22.42	AVG	
9.4140	38.72	9.91	48.63	60.00	11.37	QP	
9.4140	24.24	9.91	34.15	50.00	) -15.85	AVG	



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EUT:	Smart phone	L	Model Nam	del Name: A			
Temperature:	21.1℃		Relative Hu	imidity:	50%	6	
Pressure:	1010hPa 🔶	Phase:	Phase:NTest Mode:Mode:				
Test Voltage:	est Voltage: DC 5V from Adapter AC 230V/50Hz				Test Mode:	le 2	
		× 3				A	7 X
Frequency	Meter Reading	Factor	Emission Level	Limit	s	Margin	Demeril
(MHz)	(dBµV)	(dB)	(dBµV)	(dBµ\	/)	(dB)	Remark
0.6097	38.36	9.67	48.03	56.0	0	-7.97	QP
0.6097	32.08	9.67	41.75	46.0	0	-4.25	AVG
0.6740	34.30	9.67	43.97	56.0	0	-12.03	QP
0.6740	26.05	9.67	35.72	46.0	0	-10.28	AVG
1.1019	30.63	9.68	40.31	56.0	0	-15.69	QP
1.1019	24.25	9.68	33.93	46.0	0	-12.07	AVG
1.6417 🧷	30.32	9.67	39.99	56.0	0	-16.01	QP
1.6417	20.61	9.67	30.28	46.0	0	-15.72	AVG
2.5579	30.24	9.69	39.93	56.0	0	-16.07	QP
2.5579	17.64	9.69	27.33	46.0	0	-18.67	AVG
10.0816	38.66	9.90	48.56	60.0	0	-11.44	QP QP
10.0816	18.06	9.90	27.96	50.0	0	-22.04	AVG

### Remark:

All readings are Quasi-Peak and Average values.
 Factor = Insertion Loss + Cable Loss.





Note: The test modes were carried out for all operation modes. The worst test mode for test data was showed in the report.

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### 3.2 RADIATED EMISSION MEASUREMENT

### 3.2.1 LIMITS OF RADIATED EMISSION MEASUREMENT (Below 1000MHz)

## Table A.2 – Requirements for radiated emissions at frequencies up to 1 GHz for Class A equipment

Table clause	Frequency range	Frequency range Measurement		Class A limits dB(µV/m)	
	MHz	Distance m	Detector type/ bandwidth	OATS/SAC (see Table A.1)	
A2.1	30 – 230	10		40	
	230 – 1 000	10	Quasi Peak /	47	
A2.2	30 – 230	2	120 kHz	50	
	230 – 1 000	5		57	

Apply only A2.1 or A2.2 across the entire frequency range.

#### Table A.4 – Requirements for radiated emissions at frequencies up to 1 GHz for Class B equipment

Table Frequency range		Me	easurement	Class B limits dB(µV/m)		
	MHz	Distance m	Detector type/ bandwidth	OATS/SAC (see Table A.1)		
A4.1	30 – 230	10		30		
	230 – 1 000	10	Quasi Peak /	37		
A4.2	30 – 230	2	120 kHz	40		
	230 – 1 000	ى ا		47		

Apply only table clause A4.1 or A4.2 across the entire frequency range.

### Table A.6 – Requirements for radiated emissions from FM receivers

Table	Frequency range	Me	easurement	Class B lim	it dB(μV/m)	
clause	MHZ	Distance Detector type/		Fundamental	Harmonics	
		m	pandwidtn	OATS/SAC (see Table A.1)	OATS/SAC (see Table A.1)	
A6.1	30 – 230				42	
	230 – 300	10		50	42	
	300 – 1 000		Quasi peak/		46	
A6.2	30 – 230		120 kHz		52	
	230 – 300	3		60	52	
	300 – 1 000				56	

Apply only A.6.1 or A.6.2 across the entire frequency range.

These relaxed limits apply only to emissions at the fundamental and harmonic frequencies of the local oscillator. Signals at all other frequencies shall be compliant with the limits given in Table A.4.

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### 3.2.2 LIMITS OF RADIATED EMISSION MEASUREMENT (Above 1000MHz)

## Table A.3 – Requirements for radiated emissions at frequencies above 1 GHz for Class A equipment

Table clause	Frequency range	Me	easurement	Class A limits dB(µV/m)
	MHz Distance Detector m bandwi		Detector type/ bandwidth	FSOATS (see Table A.1)
A3.1	1 000 – 3 000		Average /	56
	3 000 - 6 000	2	1 MHz	60
A3.2	1 000 – 3 000	3	Peak /	76
	3 000 - 6 000		1 MHz	80

Apply A3.1 and A3.2 across the frequency range from 1 000 MHz to the highest required frequency of measurement derived from Table 1.

## Table A.5 – Requirements for radiated emissions at frequencies above 1 GHz for Class B equipment

Table	Frequency range	Me	easurement	Class B limits dB(µV/m)
clause	MHz	Distance Detector type/ m bandwidth		FSOATS (see Table A.1)
A5.1	1 000 – 3 000		Average/	50
	3 000 – 6 000	3	1 MHz	54
A5.2	1 000 – 3 000		Peak/	70
	3 000 – 6 000		1 MHz	74

Apply A5.1 and A5.2 across the frequency range from 1 000 MHz to the highest required frequency of measurement derived from Table 1.

#### Notes:

- (1) The limit for radiated test was performed according to as following: CISPR 32.
- (2) The tighter limit applies at the band edges.
- (3) Emission level  $(dB\mu V/m)=20log$  Emission level (uV/m).

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## 3.2.3 TEST PROCEDURE

- a. The measuring distance of at 3 m shall be used for measurements at frequency up to 1GHz. For frequencies above 1GHz, any suitable measuring distance may be used.
- b. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 10 meter open area test site. The table was rotated 360 degrees to determine the position of the highest radiation.
- c. The height of the equipment or of the substitution antenna shall be 0.8 m; the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. The initial step in collecting conducted emission data is a spectrum analyzer peak detector mode pre-scanning the measurement frequency range. Significant peaks are then marked and then Quasi Peak detector mode re-measured.
- e. If the Peak Mode measured value compliance with and lower than Quasi Peak Mode Limit, the EUT shall be deemed to meet QP Limits and then no additional QP Mode measurement performed.
- f. For the actual test configuration, please refer to the related Item -EUT Test Photos.

## 3.2.4 TEST SETUP

(A) Radiated Emission Test Set-Up Frequency Below 1 GHz



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(B) Radiated Emission Test Set-Up Frequency Above 1GHz



## 3.2.5 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of **2.2** Unless otherwise a special operating condition is specified in the follows during the testing.



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## 3.2.6 TEST RESULTS (30-1000MHz)

_01.	Smart phone			Model Name: A5			A53		
emperature:	<b>23.9℃</b>		X	Relative H	umidity:	52%	2%		
Pressure:	1010 hPa			Polarization: Ve		Verti	/ertical		
Test Power: DC 5V from Adapter AC 230V/50Hz				Test Mode: Mode 2					
			×						
Frequency	Meter Reading	Factor	Emiss	ion Level	Limit	ts	Mar	rgin	Bomar
(MHz)	(dBµV)	(dB)	(dB	βµV/m)	(dBµV	/m)	(dl	B)	rteman
33.2112	8.38	24.28	3	2.66	40.0	0	-7.	34	QP
40.8446	11.18	20.08	3	1.26	40.0	0	-8.	74	QP
183.2005	19.67	16.73	3	6.40	40.0	0	-3.	60	QP
266.6089	13.20	19.57	3	2.77	47.0	0	-14	.23	QP
919.2866	7.45	30.63	3	8.08	47.0	0	-8.	92	QP
1000.000	6.52	31.95	3	8.47	47.0	0	-8.	53	QP
72.0 dBuV/m						2		Limit: Margin:	_
72.0 dBu¥/m						2		Limit: Margin:	
72.0 dBuV/m								Limit: Margin:	
72.0 dBuV/m								Limit: Margin:	5.6
72.0 dBuV/m								Limit: Margin:	
72.0 dBuV/m 32 1 2 32 1 2			Jundan				al a factor of the second	Limit: Margin:	S S
72.0 dBuV/m	Manna and a second	arte way to any with	will your of the contract of t			and the second	al a factor of the second	Limit: Margin:	5.5
72.0 dBuV/m	Manna and a second	er waard and a second and a s	adhan dha			al and the set		Limit: Margin:	5 6 
72.0 dBuV/m		en openson of the second se	with second			and the second	u/u/weekeed	Limit: Margin:	S S
72.0 dBuV/m	Manna and a second	Article Antipologies and a second and a se	will and the second					Limit: Margin:	5-6
72.0 dBuV/m	50 60 70 80	arte and a second	MHz)		300	400	4444444444	Limit: Margin:	5.6
72.0 dBuV/m	50 60 70 80		(MHz)			400	500 64	Limit: Margin:	5.5
72.0 dBuV/m	50 60 70 80		(MHz)		300	400	500 61	Limit: Margin: Margin: Margin: 00 700	5.5 5.5 1000.000

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EUT:	Smart phone	Model Name:	A53
Temperature:	24.5℃	Relative Humidity:	51%
Pressure:	1010 hPa	Polarization:	Horizontal
Test Power:	DC 5V from Adapter AC 230V/50Hz	Test Mode:	Mode 2

						÷
Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Pomark
(MHz)	(dBµV)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	nemark
30.5304	6.28	25.87	32.15	40.00	-7.85	QP
185.1379	18.03	16.85	34.88	40.00	-5.12	QP
280.0237	15.81	20.08	35.89	47.00	-11.11	QP
747.4825	6.83	28.74	35.57	47.00	-11.43	QP
848.0561	7.53	29.85	37.38	47.00	-9.62	QP
942.1304	7.87	30.99	38.86	47.00	-8.14	QP

Remark:

1. Emission Level= Meter Reading+ Factor, Margin= Emission Level- Limit.



Note: The test modes were carried out for all operation modes. The worst test mode for test data was showed in the report.

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## 3.2.7 TEST RESULTS(1000-6000MHz)

EUT:	Smart phone	Model Name:	A53		
Temperature:	<b>24.5</b> ℃	Relative Humidity:	51%		
Pressure:	1010 hPa 📃 🔨	Test Mode:	Mode 2	. (	
Test Power:	DC 5V from Adapter AC 230V/50Hz				1

Polar	Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Remark	
(H/V)	(MHz)	(dBµV/m)	(dB)	(dBµV/m)	(dBµV/m)	(dB)	nomark	
V	1325.000	39.83	7.39	47.22	70.00	-22.78	peak	
v	1325.000	29.48	7.39	36.87	50.00	-13.13	AVG	
V	1687.500	39.42	8.13	47.55	70.00	-22.45	peak	
V	1687.500	29.19	8.13	37.32	50.00	-12.68	AVG	
V	2100.000	37.65	11.59	49.24	70.00	-20.76	peak	
V	2100.000	27.65	11.59	39.24	50.00	-10.76	AVG	
V	2900.000	38.16	11.82	49.98	70.00	-20.02	peak	
V	2900.000	28.32	11.82	40.14	50.00	-9.86	AVG	
V	4250.000	37.86	17.91	55.77	74.00	-18.23	peak	
V	4250.000	24.20	17.91	42.11	54.00	-11.89	AVG	
V –	4800.000	36.88	19.72	56.60	74.00	-17.40	peak	
V	4800.000	23.64	19.72	43.36	54.00	-10.64	AVG	
н	2137.500	36.85	11.38	48.23	70.00	-21.77	peak	
Н	2137.500	26.76	11.38	38.14	50.00	-11.86	AVG	
ЮН	2850.000	37.92	11.69	49.61	70.00	-20.39	peak 🎺	
Н	2850.000	27.66	11.69	39.35	50.00	-10.65	AVG	
Н	3837.500	36.01	15.61	51.62	74.00	-22.38	peak	
Н	3837.500	24.79	15.61	40.40	54.00	-13.60	AVG	
Н	4350.000	37.46	18.05	55.51	74.00	-18.49	peak	
Н	4350.000	23.19	18.05	41.24	54.00	-12.76	AVG	
н	4800.000	36.02	19.72	55.74	74.00	-18.26	peak	
Н	4800.000	23.43	19.72	43.15	54.00	-10.85	AVG	
Н	5400.000	35.81	18.85	54.66	74.00	-19.34	peak	
Н	5400.000	23.45	18.85	42.30	54.00	-11.70	AVG	

Remark: Emission Level= Meter Reading+ Factor, Margin= Emission Level- Limit

Note: The test modes were carried out for all operation modes. The worst test mode for test data was showed in the report.

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## 3.3 HARMONICS CURRENT

## 3.3.1LIMITS OF HARMONICS CURRENT

Table 1 – Limits for Class A equipment

Harmonic order (n)	Maximum permissible harmonic current (A)			
Odd h	narmonics			
3	2.3			
5	1.14			
7	0.77			
9	0.4			
11 🔶	0.33			
13	0.21			
15≤n≤39	0.15*(15/n)			
Even I	narmonics			
2	1.08			
4	0.43			
6	0.30			
8≤n≤40	0.23*(8/n)			

Note: Reference standard of the table above: EN61000-3-2.



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## 3.3.2 TEST PROCEDURE

a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions.

b. The classification of EUT is according to section 5 of EN 61000-3-2. The EUT is classified as follows:

Class A: Balanced three-phase equipment, Household appliances excluding equipment as Class D, Tools excluding portable tools, Dimmers for incandescent lamps, audio equipment, equipment not specified in one of the three other classes.

Class B: Portable tools. Portable tools.; Arc welding equipment which is not professional equipment.

Class C: Lighting equipment.

Class D: Equipment having a specified power less than or equal to 600W of the following types: Personal computers and personal computer monitors and television receivers.

c. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

## 3.3.3 EUT OPERATING CONDITIONS

3.3.4 TEST SETUP

The EUT tested system was configured as the statements of 2.3 Unless otherwise a special operating condition is specified in the follows during the testing.

# Voltage Supply To AC Mains Power Supply Power Analyzer & Power Source EUT Non-Metallic Table

N2017.03.22.0322.V.1.0

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## 3.3.5 TEST RESULTS

EUT:	Smart phone	Model Name:	A53	7	
Temperature:	<b>22℃</b>	Relative Humidity:	53%		
Pressure:	1012hPa	Test duration:	150s	1	
Classification:	Class A	Test Power:	N/A		~
Test Mode:	N/A		<u></u>	5	

Note: The active input power of the EUT is less than 75 W. No limits apply for equipment with an active input power up to and including 75W.

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## 3.4 VOLTAGE FLUCTUATION AND FLICKERS

## 3.4.1 LIMITS OF VOLTAGE FLUCTUATION AND FLICKERS

Test items		Limits(EN61000-3-3)	Descriptions		
	P <sub>st</sub>	≤1.0, T <sub>p</sub> =10min	short-term flicker indicator		
	P <sub>lt</sub>	≪0.65, T <sub>p</sub> =2h	long-term flicker indicator		
	d <sub>c</sub>	≤3.3%	relative steady-state voltage change		
	d <sub>max</sub>	≪4%(or 6% <sub>Note(1)</sub> , 7% <sub>Note(2)</sub> )	maximum relative voltage change:		
	d <sub>(t)</sub>	≤3.3%, more than 500ms	relative voltage change characteristic		

### Note:

- 1. 6 % for equipment which is:
  - a. switched manually, or

b. switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.

## 2. 7 % for equipment which is

a. attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or b. switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

## 3.4.2 TEST PROCEDURE

a. Harmonic Current Test:

Test was performed according to the procedures specified in Sub-clause 6.2 of IEC/EN 61000-3-2 depend on which standard adopted for compliance measurement.

b. Fluctuation and Flickers Test:

Tests was performed according to the Test Conditions/Assessment of Voltage Fluctuations specified in Clause 6.0/4.0 of IEC/EN 61000-3-3 depend on which standard adopted for compliance measurement.

c. All types of harmonic current and/or voltage fluctuation in this report are assessed by direct measurement using flicker-meter.

## 3.4.3 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of 2.3 Unless otherwise a special operating condition is specified in the follows during the testing.

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#### 3.4.5 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22.2</b> °C	Relative Humidity:	52%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz
Test Mode:	Mode 1		
			<b>7</b>

	EUT values	Limit	Result
Pst	0.028	1.00	PASS
Plt	0.028	0.65	PASS
dc [%]	0.000	3.30	PASS
dmax [%]	0.180	7.00	PASS
Tmax [s]	0.000	0.50	PASS



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#### 4. EMC IMMUNITY TEST

#### 4.1 GENERAL PERFORMANCE CRITERIA

#### 4.1.1 PERFORMANCE CRITERIA

According to EN 55035 standard, the general performance criteria as following:

Criterion BThe equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.Criterion AThe performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.Criterion BAfter the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.Criterion BCriterion is allowed, after the application of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		
<ul> <li>intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.</li> <li>Criterion A</li> <li>The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.</li> <li>After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level</li> <li>specified by the manufacturer, when the equipment is used as intended.</li> <li>The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.</li> <li>Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.</li> <li>Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</li> </ul>		The equipment shall continue to operate as intended without operator
Criterion Aperformance level specified by the manufacturer when the equipment is used as intended.Criterion AThe performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.Criterion BAfter the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.Criterion BCriterion BCriterion BLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		intervention. No degradation of performance or loss of function is allowed below a
Criterion AIntended.Criterion AThe performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.Criterion BSpecified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		performance level specified by the manufacturer when the equipment is used as
Criterion AThe performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.AAfter the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.Criterion BSpecified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		intended.
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specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.Criterion BPreformance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		the minimum performance level or the permissible performance loss is not
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Criterion BAfter the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		expect from the equipment if used as intended.
<ul> <li>Criterion B</li> <li>operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.</li> <li>Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</li> </ul>		After the test, the equipment shall continue to operate as intended without
Criterion Ballowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Criterion CLoss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		operator intervention. No degradation of performance or loss of function is
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The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.	<b>Criterion B</b>	specified by the manufacturer, when the equipment is used as intended.
During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.Criterion CFunctions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		The performance level may be replaced by a permissible loss of performance.
operating state or stored data is allowed to persist after the test.Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		During the test, degradation of performance is allowed. However, no change of
<ul> <li>Criterion C</li> <li>Criterion C</li> <li>Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.</li> <li>Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.</li> </ul>		operating state or stored data is allowed to persist after the test.
Criterion C restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		Loss of function is allowed, provided the function is self-recoverable, or can be
Criterion C manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.		restored by the operation of the controls by the user in accordance with the
Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.	<b>Criterion</b> C	manufacturer's instructions.
battery backup, shall not be lost.		Functions, and/or information stored in non-volatile memory, or protected by a
		battery backup, shall not be lost.

According to EN 301 489-3 standard, the general performance criteria as following:

C	Criteria	During the test	After the test					
		Operate as intended	Operate as intended					
		No loss of function	No loss of function					
A	A	No unintentional responses	No degradation of performance					
			No loss of stored data or user programmable					
	X		functions					
		S. C	Operate as intended					
		May show loss of function	Lost function(s) shall be self-recoverable					
E	3	No unintentional responses	No degradation of performance					
		No unintentional responses	No loss of stored data or user programmable					
	*		functions					

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Criteria	During the test	After the test
1	Shall operate as intended (see note 1).	Shall operate as intended.
	Shall be no loss of function.	Shall be no degradation of performance
	Shall be no unintentional	(see note 3).
A	transmissions	Shall be no loss of function.
		Shall be no loss of stored data or user
1		programmable functions
	May show loss of function (one or	Functions shall be self-recoverable.
	more).	Shall operate as intended after recovering.
Р	May show degradation of performance	Shall be no degradation of performance
Б	(see note 2).	(see note 3).
	Shall be no unintentional	Shall be no loss of stored data or user
	transmissions.	programmable functions.
		Functions shall be recoverable by the
	2	operator.
с 🚽	May be loss of function (one or more)	Shall operate as intended after recovering.
		Shall be no degradation of performance
		(see note 3).

NOTE 1: Operate as intended during the test allows a level of degradation not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended. NOTE 2: Degradation of performance during the test is understood as a degradation to a level not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance.

If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.

NOTE 3: No degradation of performance after the test is understood as no degradation below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. After the test no change of actual operating data or user retrievable data is allowed. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.

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According to EN 301 489-19 standard, the general performance criteria as following:

If the EUT is of a non specialized nature or the EUT is combined with an ancillary equipment, the test modulation, test arrangements, etc. as required in clause 4 shall apply.

The EUT, for all immunity tests according to the present document, except the spot frequency test of the immunity test with radiated RF electromagnetic fields (see ETSI EN 301 489-1 [1], clause 9.2), shall be assessed for:

• the storage of messages in the memory of the EUT at the start of the test;

- unintentional responses of the EUT during the test;
- the maintenance of the EUT memory assessed at the conclusion of the test;

• the ability to receive and store messages at the conclusion of the test.

For the spot frequency test of the immunity test with radiated RF electromagnetic fields (see ETSI EN 301 489-1 [1], clause 9.2) the EUT shall be assessed by monitoring the accuracy of the call received alert signal.

### Performance criteria for Continuous phenomena applied to ROMES and ROGNSS receivers (CR)

For the EUT, excluding spot frequency tests as part of the immunity test with radiated RF electromagnetic fields (see ETSI EN 301 489-1 [1], clause 9.2):

- the general performance criteria set out in clause 6.1;
- during the test no false calls shall occur;

• at the conclusion of the test comprising the series of individual exposures the EUT shall operate as intended with no loss of functions or stored data (messages), as declared by the manufacturer.

For the spot frequency test as part of the immunity test with radiated RF electromagnetic fields (see ETSI EN 301 489-1 [1], clause 9.2) the EUT shall be assessed by monitoring the accuracy of the call received alert signal.

### Performance criteria for Transient phenomena applied to ROMES and ROGNSS receivers (TR)

For the EUT:

- the general performance criteria set out in clause 6.1;
- during the test no false calls shall occur;
- at the conclusion of the test comprising the series of individual exposures, the EUT shall operate as intended with no loss of function and/or stored data (messages), as declared by the manufacturer.

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### Special conditions for EMC immunity tests Table 2: Special conditions for EMC immunity tests

Reference to clauses in ETSI EN 301 489-1 [1]	Special product-related conditions, additional to or modifying the test conditions in ETSI EN 301 489-1 [1], clause 9
9.1 Test configuration; Test methods and levels for immunity tests	The message memory shall be loaded with recognizable messages. The EUT shall operate in stand-by mode of operation, except for the spot frequency test as part of the immunity test with radiated RF electromagnetic fields (see ETSI EN 301 489-1 [1], clause 9.2) where repetitive calls shall be coupled to the input of the receiver. • for the immunity tests of ancillary equipment, without a separate pass/fail criteria, an EUT coupled to the ancillary equipment shall be used to judge whether the ancillary equipment passes or fails.
9.2.2 Test method; Radio frequency electromagnetic field	Spot frequency test:         A spot frequency test shall additionally be performed at:         80 MHz;         104 MHz;         136 MHz;         165 MHz;         200 MHz;         260 MHz;         330 MHz;         430 MHz;         560 MHz;         560 MHz;         a spot frequency test shall be performed at 920 MHz ± 1 MHz         using a test level of 3 V/m (measured unmodulated) 100 %         modulated by 200 Hz pulses of equal mark to space ratio.

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#### PERFORMANCE FOR TT

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an acknowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

#### PERFORMANCE FOR TR

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration for which performance criteria C shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

#### PERFORMANCE FOR CT

The performance criteria A shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an Acknowledgement (ACK) or Not Acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

#### PERFORMANCE FOR CR

The performance criteria A shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

According to EN 301 489-52 standard, the general performance criteria as following:

GSM and DCS Performance Criteria Please refer to the standard ETSI EN 301 489-52 V1.2.1 clause 6.1.

**CDMA Direct Spread (UTRA and E-UTRA) Performance Criteria** Please refer to the standard ETSI EN 301 489-52 V1.2.1 clause 6.2.

#### 4.2 GENERAL PERFORMANCE CRITERIA TEST SETUP The EUT tested system was configured as the statements of **2.2** Unless otherwise a special

operating condition is specified in the follows during the testing.

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#### 4.3 ESD TESTING

#### 4.3.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-2
Discharge Impedance:	330 ohm / 150 pF
Required Performance	В
Discharge Voltage:	Air Discharge: 2kV/4kV/8kV
	Contact Discharge: 2kV/4kV (Direct/Indirect)
Polarity:	Positive & Negative
Number of Discharge:	Air Discharge: min. 20 times at each test point
	Contact Discharge: min. 200 times in total
Discharge Mode:	A/C Discharge
Discharge Period:	1 second minimum

#### 4.3.2 TEST PROCEDURE

The test generator necessary to perform direct and indirect application of discharges to the EUT in the following manner:

- a. Indirect application of the discharge:
  - Vertical Coupling Plane (VCP):

At least 10 single discharges (in the most sensitive polarity) shall be applied to the centre of one vertical edge of the coupling plane. The coupling plane, of dimensions 0,5 m  $\times$  0,5 m, is placed parallel to, and positioned at a distance of 0,1 m from, the EUT.

Discharges shall be applied to the coupling plane, with sufficient different positions such that the four faces of the EUT are completely illuminated. One VCP position is considered to illuminate 0,5 m  $\times$  0,5 m area of the EUT surface.

#### Horizontal Coupling Plane (HCP):

Discharge to the HCP shall be made horizontally to the edge of the HCP.

At least 10 single discharges (in the most sensitive polarity) shall be applied at the front edge of each HCP opposite the centre point of each unit (if applicable) of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

The discharge electrode shall be in contact with the edge of the HCP before the discharge switch is operated

b. Direct application of discharges to the EUT

The test shall be performed with single discharges. On each pre-selected point at least 10 single discharges (in the most sensitive polarity) shall be applied.

For the time interval between successive single discharges an initial value of 1 s is recommended. Longer intervals may be necessary to determine whether a system failure has occurred.

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#### 4.3.3 TEST SETUP



#### Note:

#### TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table 0.8 meters high standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum at least 0.25mm thick, and 2.5 meters square connected to the protective grounding system. A Horizontal Coupling Plane (1.6m x 0.8m) was placed on the table and attached to the GRP by means of a cable with 940k total impedance. The equipment under test, was installed in a representative system as described in section 7 of IEC /EN 61000-4-2, and its cables were placed on the HCP and isolated by an insulating support of 0.5mm thickness. A distance of1-meter minimum was provided between the EUT and the walls of the laboratory and any other metallic structure.

#### FLOOR-STANDING EQUIPMENT

The equipment under test was installed in a representative system as described in section 7 of IEC/EN 61000-4-2, and its cables were isolated from the Ground Reference Plane by an insulating support of 0.1-meter thickness. The GRP consisted of a sheet of aluminum that is at least 0.25mm thick, and 2.5meters square connected to the protective grounding system and extended at least 0.5 meters from the EUT on all sides.

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#### 4.3.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22</b> ℃	Relative Humidity:	53%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz / DC 5V from PC
Test Mode:	Mode 1/2/3/4/5/6/7/8/9/10		At S

	Mode	Contact D	isch	arg	ə (Ir	ndire	ect)					
	Test level(kV)	Tost Point	2	2	2	1	6	6	Criterion	Result		
	Test Location		+	-	+	-	+	-				
	1	Front	Ρ	Ρ	Ρ	Ρ						
	HCP	Rear	Ρ	Ρ	Ρ	Ρ				t t		
		Left	Ρ	Ρ	Ρ	Ρ			×			
		Right	Ρ	Ρ	Ρ	Ρ	大			Complian		
	1	Front	Ρ	Р	Ρ	P			Р	Complies		
	VCP	Rear	Ρ	Ρ	Ρ	Ρ				, A		
		Left	Ρ	Ρ	Ρ	Ρ						
		Right	Ρ	Ρ	Ρ	Ρ			SV SV			

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#### TEST RESULT

Mode		A	Air I	Dis	cha	arg	е		(	Соі	nta	ct [	Diso	cha	irge	Э	BT / WIFI				
Test level(kV)	4	2	2	1	8	3	1	5		2	4 6 8		WCDMA /ITF	GPS Obser	Crite rion	Result					
Test Location	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-	Observati on	vation			
A1	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ											<u>``</u>				
A2	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ									V						
A3	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ				V	· ·							F		4	
A4	Ρ	Ρ	Ρ	Ρ	Ρ	Р										ł	тт тр	тр	В	Complias	
A5	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ					ł						11,10		В	Complies	
A6	Ρ	Ρ	Ρ	Ρ	Ρ	Р														X	
A7	Ρ	Ρ	Ρ	P	Ρ	Ρ											1 A	4		A.C.	
A8 🔨	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ											S <sup>(V</sup>				



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#### Mode 1/2/3/4

Mode		A	ir I	Dis	cha	arg	е		(	Cor	ntao	ct D	Disc	cha	rge	÷			
Test level(kV)	2	2	4	ŀ	ε	3	15		2	2		4		6		3	Crite rion	Result	
Test Location	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-			
A1	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ											Y	5	
A2	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ										$\mathbb{R}$			
A3	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ													
A4	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ	1.											Complian	
A5	Ρ	Р	Ρ	Ρ	Ρ	Ρ										A.	В	Complies	
A6	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ					<b>S</b>								
A7	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ													
A8	Ρ	Ρ	Ρ	Ρ	Ρ	Ρ												<u> </u>	
	Mode Test level(kV) Test Location A1 A2 A3 A3 A4 A5 A6 A7 A8	ModeTest level(kV)Test Location4A1A2PA3A4PA5PA6PA7PA8	ModeImage: Additional symbolTest level(kV)2Test Location+A1PA2PA3PA3PA4PA5PA6PA7PA8P	Mode $\lor$ integralTest level(kV) $2 \cdot$ $2 \cdot$ Test Location $+$ $-$ A1PPA2PPA3PPA4PPA5PPA6PPA7PPA8PP	ModeJurn InternationTest level(kV) $2$ $4$ Test Location+-++-A1PPPPPA2PPPPPA3PPPPPA3PPPPPA3PPPPPA4PPPPPA5PPPPPA6PPPPA8PPPP	ModeAir DischarTest level(kV)2 $4 \cdot 5$ $4 \cdot 5$ $4 \cdot 5$ Test Location+-+-+A1PPPPPA2PPPPPA3PPPPPA4PPPPPA5PPPPPA6PPPPPA8PPPPP	ModeAir DisclarationTest level(kV) $2$ $4$ $8$ Test Location+-++-+-A1PPPPPPPA2PPPPPPPA3PPPPPPPA3PPPPPPPA4PPPPPPPA5PPPPPPPA6PPPPPPA8PPPPPP	Mode $Air viscular v$	Mode $I = V I I I I I I I I I I I I I I I I I $	Mode $\exists I : I : I : I : I : I : I : I : I : I $	Mode $I = I = I = I = I = I = I = I = I = I =$	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Mode       Substrate Strate       Contact In the strate         Test level(kV) $2^{-}$ $4^{-}$ $8^{-}$ $1^{-}$ $2^{-}$ $4^{-}$ Test Location $+$ $ +$	Mode       Series S	Mode       Securate USENTION         Test level(kV) $2^{-}$ $4^{-}$ $8^{-}$ $1^{-}$ $2^{-}$ $4^{-}$	Mode       Air Discharge       Contact Discharge         Test level(kV)       2       4       8       15       2       4       6       8         Test Location       +       -       +	$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	$ \begin{array}{ c c c c c c c c c c } \hline \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$

#### Note:

1) +/- denotes the Positive/Negative polarity of the output voltage.

2) In the table: 'P' represents 'PASS'; 'F' represents 'FAIL'.

3) There was not any unintentional transmission in standby mode.



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# NTEK 北测<sup>®</sup> Page 48 of 74 4.3.5 PHOTO(S) SHOWN THE LOCATION(S) OF ESD EVALUATED Photo 1 A2 Photo 2



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#### 4.4 RS TESTING

#### 4.4.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-3
Required Performance	A
Frequency Range:	According to EN 301 489-1:
	80 MHz - 6000 MHz ;
	According to EN 55035:
	80 MHz to 1000 MHz
	1800 MHz
	2600 MHz 🙏
	3500 MHz
	5000 MHz
Field Strength:	3 V/m
Modulation:	1kHz Sine Wave, 80%, AM Modulation
Frequency Step:	1 % of fundamental
Polarity of Antenna:	Horizontal and Vertical
Test Distance:	3 m 🗡 🖉 🍣
Antenna Height:	1.5 m -
Dwell Time:	at least 3 seconds

#### 4.4.2 TEST PROCEDURE

The EUT and support equipment, which are placed on a table that is 0.8 meter above ground and the testing was performed in a fully-anechoic chamber.

The testing distance from antenna to the EUT was 3 meters.

The other condition as following manner:

- a. The field strength level was 3V/m.
- b. The frequency range is swept from 80 MHz to 6000 MHz, 1800 MHz, 2600 MHz, 3500 MHz, 5000 MHz with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5 x 10<sup>-3</sup> decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. Sweep Frequency 900 MHz, with the Duty Cycle:1/8 and Modulation: Pulse 217 Hz(if applicable)
- d. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- e. The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.
- f. For the actual test configuration, please refer to the related Item -EUT Test Photos.

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#### Note:

For the actual test configuration, please refer to the related Item -EUT Test Photos.

#### TABLE-TOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

#### FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

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#### 4.4.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>23</b> ℃	Relative Humidity:	57%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz / DC 5V from PC
Test Mode:	Mode 1/2/3/4/5/6/7/8/9/10		A A

#### TEST RESULT

#### LTE FDD B1 / B3 / B7 / B8 / B20 / B40 Data Link

Frequency Range	RF Field	R.F.	Azimuth	Observation	Populto
(MHz)	Position	Field Strength	Azimum	Observation	nesuiis
~ ~		2)//m (rma)	Front		
80~1000		3 V/m (rms)	Rear	OT OD	
1000-6000			Left	CI,CR	
		100012, 00%	Right		

#### Note:

The exclusion band has not been tested in 80MHz~6GHz.
 For channelized equipment the exclusion band shall be calculated by using the following formulae:

For the lower edge for the exclusion band:

EXband(lower) = BandRX(lower) - nChWRX

and for the upper edge of the exclusion band:

EXband(upper) = BandRX(upper) + nChWRX

- Where n = number of channel widths required for exclusion band.
- 2. In the data transfer mode, the performance criteria shall be that the throughput shall be  $\geq$  95 % of the maximum throughput of the reference measurement channel

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GSM 900 / 1800 / W	/CDMA 210	00 / 900 Uplink a	and Downlin	k		
Frequency Range	RF Field	R.F.	Azimuth	Observation	Perform.	Poculto
(MHz)	Position	Position   Field Strength   Azimuth		Observation	Criteria	nesuits
			Front			
80~1000	н/у	3 V/m (rms) AM Modulated	Rear	OT OB		
1000-6000			Left	CI,CR		P
A S		1000112, 0078	Right			

#### Note:

1. The exclusion band has not been tested in 80MHz~6GHz.

For channelized equipment the exclusion band shall be calculated by using the following formulae:

For the lower edge for the exclusion band:

EXband(lower) = BandRX(lower) - nChWRX

and for the upper edge of the exclusion band:

EXband(upper) = BandRX(upper) + nChWRX

Where n = number of channel widths required for exclusion band.

2: "A" stand for: the uplink/downlink speech output level shall be at least 35 dB less than the previously recorded reference levels, when measured through an audio band pass filter of width 200 Hz, centred on 1 kHz (audio breakthrough check). The RXQUAL of the downlink is not exceeding the value of three, measured during each individual exposure in the test sequence. Or During and after the test, the apparatus continue to operate as intended. No degradation of performance or loss of function is allowed below a permissible performance level.

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#### GPRS / EGPRS / HSDPA / HSUPA Uplink and Downlink

Frequency	RF Field	R.F.	Azimuth	Observation	Perform.	Results
Range (MHz)	Position	Field Strength			Criteria	
~	H/V	2 Mm (rma)	Front		A _	
80~1000		AM Modulated	Rear	СТСР		Р
1000-6000			Left	CI,CR		
		100012, 80 %	Right			

#### Note:

1. The exclusion band has not been tested in 80MHz~6GHz.

For channelized equipment the exclusion band shall be calculated by using the following formulae:

For the lower edge for the exclusion band:

EXband(lower) = BandRX(lower) - nChWRX

and for the upper edge of the exclusion band:

EXband(upper) = BandRX(upper) + nChWRX

Where n = number of channel widths required for exclusion band.

2. During the test, the Maximum Bit Error Ratio was less than 1×10<sup>-3</sup>.

3. During the test, the Maximum Block Error Ratio was less than 1×10<sup>-2</sup>.

#### BT / WIFI link

Frequency	RF Field	R.F.	∆zimuth	Observation	Perform.	Results
Range (MHz)	Position	Field Strength	Azimum	Observation	Criteria	Tiesuits
			Front	<u> </u>	A	
80~1000	H/V	3 V/m (rms) AM Modulated	Rear	OT OD		
1000-6000			Left	CI,CR		P
		1000112, 00 %	Right			

Note:

- 1. The exclusion band has not been tested in 80MHz~6GHz.
- The exclusion band for immunity testing of equipment operating in the 2,4 GHz band shall be: lower limit of exclusion band = lowest allocated band edge frequency -120 MHz, i.e. 2 280 MHz; • upper limit of exclusion band = highest allocated band edge frequency +120 MHz, i.e. 2 603,5MHz.
- 2. "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions.

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GPS Receiver Mod	le Link	1 ×			6	
Frequency Range	RF Field	R.F.	Azimuth	Observation	Perform.	Doculto
(MHz)	Position	Field Strength	Azimum	Observation	Criteria	nesuits
5		- *	Front			
80~1000	н/	3 V/m (rms) AM Modulated 1000Hz, 80%	Rear			Les la
1000-6000			Left		4	F
			Right	4		×
80,104,136,			Front		X	J.V
165,200,260,	5	3 V/m (rms)	Bear			
330,430,560,	H/V	Unmodulated	ittoai	CR	Α	Р
715 MHz ± 1,		200Hz, 100%	Left			
920 MHz ± 1		N.	Right			

Note: "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions.

#### REC / TF Playing /Data Transmission / FM Mode

Frequency Range (MHz)	RF Field Position	R.F. Field Strength	Azimuth	Perform. Criteria	Results
80~1000		1	Front		×-
1800		3 V/m (rms)	Rear	A.	
2600		1000Hz, 80%	Left	A	F
3500 5000			Right		* *

Note: "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions. There was not any unintentional transmission in standby mode.

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#### 4.5 EFT/BURST TESTING

#### 4.5.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-4
Required Performance	B
Test Voltage:	Power Line: 1 kV
	DC/Signal/ wired network Line: 0.5 KV
Polarity:	Positive & Negative
Impulse Frequency:	For xDSL wired network ports: 100 kHz
	For DC/AC ports: 5 kHz
Impulse Wave shape :	5/50 ns
Burst Duration:	15 ms
Burst Period:	300 ms
Test Duration:	Not less than 1 min.

#### 4.5.2 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m\*1m min. and 0.65mm thick min.

The other condition as following manner:

- a. The length of power cord between the coupling device and the EUT should not exceed 1 meter.
- b. Both positive and negative polarity discharges were applied.
- c. The duration time of each test sequential was 1 minute
- d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

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Note:

#### TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table (0.8m high) standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system. A minimum distance of 0.5m was provided between the EUT and the walls of the laboratory or any other metallic structure. FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-4 and its cables, were isolated from the Ground Reference Plane by an insulating support that is 0.1-meter thick. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system.

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#### 4.5.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22</b> °C	Relative Humidity:	53%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz
Test Mode:	Mode 1/2/4/5/6/7/8/9/10		

#### TEST RESULT Mode 5/6/7/8/9/10

mou		10											
			Test level (kV)							BT / WIFI /	GPS		
Cou	Coupling Line	0	.5		1	2	2	2	1	GSM / WCDMA / LTE	Observ	Criteri on	Result
		+	-	+	-	+	-	+	-	Observation	ation		
	L	Ρ	Ρ	Ρ	Ρ	V	<u>.</u>				Ť	- 4	Complies
	N	Ρ	Ρ	Р	Ρ								Complies
	PE						Ŷ						
AC	L+N	Ρ	Ρ	Ρ	Ρ							1	Complies
	L+PE									TT,TR	TR	в	
	N+PE	V								* 5	- <del>C</del>		
	L+N+PE								5				
D	C Line		ł							]			
Sig	gnal Line	Ś											

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Mode 1/2/4	4		.L		~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~						dt .
				Т	est lev						
Coupli	ing Line	0	0.5 1		1		2	4		Criterion	Result
		+	-	+	-	+	-	+	-		
	ų.	Р	Р	Р	Р						Complies
1	Ň	Р	Р	Р	Р			5			Complies
	PE				~		5		7		
AC line	L+N	Р	Р	P	Р		•				Complies
	L+PE	5								В	
1	N+PE								~		
	L+N+PE					7.					
DC Line				2							
Signa	Signal Line									4	2

Note:

- 1)There was not any unintentional transmission in standby mode
- 2) In the table: 'P' represents 'PASS'; 'F' represents 'FAIL'.
- 3) There was not any unintentional transmission in standby mode.

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#### 4.6 SURGE TESTING

#### 4.6.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-5
Required Performance	B
Wave-Shape:	Combination Wave
	1.2 / 50 us Open Circuit Voltage
	8 / 20 us Short Circuit Current
Test Voltage:	Power Line:0.5 kV, 1 kV, 2 kV
Surge Input / Output:	L-N, L-PE, N-PE
Generator Source:	2 ohm between networks
Impedance:	12 ohm between network and ground
Polarity:	Positive / Negative
Phase Angle:	0 / 90 / 180 / 270
Pulse Repetition Rate:	1 time / min. (maximum)
Number of Tests:	5 positive and 5 negative at selected points

#### 4.6.2 TEST PROCEDURE

- a. For EUT power supply:
- The surge is to be applied to the EUT power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave. The power cord between the EUT and the coupling/decoupling networks shall be 2meters in length (or shorter).
- b. For test applied to unshielded unsymmetrically operated interconnection lines of EUT: The surge is applied to the lines via the capacitive coupling. The coupling /decoupling networks shall not influence the specified functional conditions of the EUT. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).
- c. For test applied to unshielded symmetrically operated interconnection /telecommunication lines of EUT:

The surge is applied to the lines via gas arrestors coupling. Test levels below the ignition point of the coupling arrestor cannot be specified. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).

d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

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# 4.6.3 TEST SETUP AC/DC Power Supply and Surge Voltage Coupling to EUT To AC Mains or DC Power Supply Combination Wave Generator Coupling Network Decoupling Network EUT D Non-Metallic Table

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#### 4.6.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22℃</b>	Relative Humidity:	53%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz
Test Mode:	Mode 1/2/4/5/6/7/8/9/10		A S

#### TEST RESULT

Mode 5/	6/7/8/9/10

					Te	est le	eve				BT / WIFI / GSM /			
Co	oupling L	ine	0.5	δkV	11	٢V	21	٢V	4kV		WCDMA	GPS Observati	Criterion	Result
			+	-	+	-	+	-	+	-	Observati on	Observati on on		
		0°	Ρ	Ρ	Ρ	Ρ	*						2	1
		90°	Ρ	Р	Р	Ρ								Complies
		180°	Р	Р	Р	Ρ	$\bigcirc$			2				
	4	270°	Ρ	Ρ	Р	Ρ						x x	x .	
		٨.									F 🔇			
AC	I-PF										TTTR	TR	B	1
line			L						V		,			
	4				ν							1 A		
		7								F				
~						L					~			
													- 4	
												~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~~		
	DC Line	9									4			
S	ignal Li	ne			F									V

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Mode 1/2/4					- Ĉ							
				Test level								
Co	oupling Line	е	0.5	kV	1	kV	2	2 kV		kV	Criterion	Result
		1	+	-	+	-	+	-	+	-		
		0°	Р	Р	Р	Р	7					ふん
		90°	Ρ	Р	Ρ	Р		1			- 2	Complies
		180°	Ρ	Ρ	Ρ	Ρ						Complies
		270°	Р	Ρ	Р	Р	ν					
	1			7						X		
AC line	I-PF	7									В	
7	· · · ·											
		×										
	+									Ł	~~``	5
	N-PF						*				, i i i i i i i i i i i i i i i i i i i	
				*		S						
		x-	Š									
X	DC Line											5
S	Signal Line							Ŕ		4	1	

Note:

- 1) There was not any unintentional transmission in standby mode
- 2) In the table: 'P' represents 'PASS'; 'F' represents 'FAIL'.
- 3) There was not any unintentional transmission in standby mode.

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#### 4.7 INJECTION CURRENT TESTING

#### 4.7.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-6
Required Performance	A
Frequency Range:	0.15 MHz - 80 MHz
Field Strength:	3 Vr.m.s.
Modulation:	1kHz Sine Wave, 80%, AM Modulation
Frequency Step:	1 % of fundamental
Dwell Time:	at least 3 seconds

#### 4.7.2 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m\*1m min. and 0.65mm thick min.

The other condition as following manner:

- a. The field strength level was 3V.
- b. The frequency range is swept from 150 KHz to 80 MHz, with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5 x 10<sup>-3</sup> decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- d. For the actual test configuration, please refer to the related Item -EUT Test Photos.

#### 4.7.3 TEST SETUP

Mobile Communication



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For the actual test configuration, please refer to the related Item –EUT Test Photos. NOTE:

#### FLOOR-STANDING EQUIPMENT

The equipment to be tested is placed on an insulating support of 0.1 meters height above a ground reference plane. All relevant cables shall be provided with the appropriate coupling and decoupling devices at a distance between 0.1 meters and 0.3 meters from the projected geometry of the EUT on the ground reference plane.

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#### 4.7.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22</b> ℃	Relative Humidity:	53%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz
Test Mode:	Mode1/2/4/5/6/7/8/9/10/11		

#### TEST RESULT LTE FDD B1 / B3 / B7 / B8 / B20 / B40Link

Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Observation	Results
Input / Output AC. Power Port	0.1580	3V(rms)	CT, CR	Р
Input / Output DC. Power Port	0.15 80	AM Modulated 1000Hz, 80%	N/A	N/A
Signal Line	0.15 80		N/A	N/A

Note: In the data transfer mode, the performance criteria shall be that the throughput shall be  $\geq$  95 % of the maximum throughput of the reference measurement channel

#### GSM 900 / 1800 / WCDMA 2100 / 900 Uplink and Downlink

Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Observation	Perform. Criteria	Results
AC. Power Port	0.1580	3V(rms)	CT, CR	۲ ۲	Р
Input / Output DC. Power Port	0.15 80	AM Modulated 1000Hz, 80%	N/A	N/A	N/A
Signal Line	0.15 80		N/A	N/A	▼ N/A

EUT is used for this calibration, the output of the audio source was adjusted to achieve a reference Level equivalent to a SPL of –5 dB Pa at 1 kHz at the Mouth Reference Point (MRP), the reading of the audio level meter, which was connected to the output of the communication tester, was recorded as a reference level. During the test, the uplink speech output level was monitored, it was confirmed to be at least 35 dB less than the previously- recorded reference level.

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3PRS / EGPRS / HSDPA / HSUPA Uplink and Downlink									
Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Observation	Perform. Criteria	Results				
Input / Output AC. Power Port	0.1580	3V(rms)	CT, CR	А	Р				
Input / Output DC. Power Port	0.15 80	AM Modulated 1000Hz, 80%	N/A	N/A	N/A				
Signal Line	0.15 80	× ×	N/A	N/A	N/A				

Note: During the test, the Maximum Bit Error Ratio was less than  $1 \times 10^{-3}$ . During the test, the Maximum Block Error Ratio was less than  $1 \times 10^{-2}$ .

#### BT / WIFI link

	4				
Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Observation	Perform. Criteria	Results
Input / Output AC. Power Port	0.1580	3V(rms)	CT, CR	Α	Р
Input / Output DC. Power Port	0.15 80	AM Modulated 1000Hz, 80%	N/A	N/A	N/A
Signal Line	0.15 80	d t	N/A	N/A	N/A

Note: "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions.

#### **GPS Receiver Mode Link**

Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Perform. Criteria	Results
Input / Output AC. Power Port	0.15 80	3V(rms)	A	Р
Input / Output DC. Power Port	0.15 80	AM Modulated 1000Hz, 80%	N/A	N/A
Signal Line	0.15 80		N/A	N/A

Note: "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions.

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#### REC / TF Playing / FM Mode

					_ <
Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Perform. Criteria	Results	
Input / Output AC. Power Port	0.1580	3V(rms)	A	P	
Input / Output DC. Power Port	0.15 80	AM Modulated	N/A	N/A	
Signal Line	0.15 80		N/A	N/A	~

Note: "A" stand for, during test, operate as intended no loss of function, no degradation of performance, no unintentional transmissions and after test, no degradation of performance, no loss of function, no loss of stored data or user programmable functions.

Note:

- 1)There was not any unintentional transmission in standby mode
- 2) In the table: 'P' represents 'PASS'; 'F' represents 'FAIL'.
- 3) There was not any unintentional transmission in standby mode.

#### 4.8 VOLTAGE INTERRUPTION/DIPS TESTING

#### 4.8.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-11
Required Performance	100% reduction, 0.5 Cycle
	100% reduction, 1.0 Cycle
	30% reduction, 25 Cycles 🧹 🛛
	30% reduction, 0.5 Cycle
Voltage Interruptions:	100% reduction, 250 Cycles
Test Duration Time:	Minimum three test events in sequence
Interval between Event:	Minimum ten seconds
Phase Angle:	0°/45°/90°/135°/180°/225°/270°/315°/360°
Test Cycle:	3 times
Voltage Interruptions: Test Duration Time: Interval between Event: Phase Angle: Test Cycle:	100% reduction, 0.5 Cycle100% reduction, 250 CyclesMinimum three test events in sequenceMinimum ten seconds0°/45°/90°/135°/180°/225°/270°/315°/360°3 times

#### 4.8.2 TEST PROCEDURE

The EUT shall be tested for each selected combination of test levels and duration with a sequence of three dips/interruptions with intervals of 10 s minimum (between each test event). Each representative mode of operation shall be tested. Abrupt changes in supply voltage shall occur at zero crossings of the voltage waveform.

#### 4.8.3 TEST SETUP



For the actual test configuration, please refer to the related Item -EUT Test Photos.

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#### 4.8.4 TEST RESULTS

EUT:	Smart phone	Model Name:	A53
Temperature:	<b>22℃</b>	Relative Humidity:	53%
Pressure:	1010 hPa	Test Power:	DC 5V from Adapter AC 230V/50Hz
Test Mode:	Mode 1/2/4/5/6/7/8/9/10		

#### TEST RESULT

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Voltage Reduction	Duration (ms)	BT / WIFI / GSM / WCDMA / LTE Observation	GPS Observation	Perform Criteria	Results	
Voltage dip: 0%	10	TT, TR	TR	В	Р	
Voltage dip: 0%	20	TT, TR	TR	В	Р	
Voltage dip: 70%	10	TT, TR	TR	С	Р	
Voltage dip: 70%	500	TT, TR	TR	С	Р	
Voltage interruptions: 0%	5000	TT, TR	TR	с	Р	

#### Mode 1/2/4

Voltage	Duration	Perform	Results	
Reduction	(ms)	Criteria		
Voltage dip: 0%	10	В	Р	
Voltage dip: 0%	20	в	Р	
Voltage dip: 70%	10	С	Р	
Voltage dip: 70%	500	С	Р	
Voltage interruptions: 0%	5000	С	Р	

#### Note:

- 1) There was not any unintentional transmission in standby mode
- 2) In the table: 'P' represents 'PASS'; 'F' represents 'FAIL'.
- 3) There was not any unintentional transmission in standby mode.

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#### 5. EUT TEST PHOTO



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# NTEK 北测<sup>®</sup>

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### **EFT Measurement Photo**

**SURGE Measurement Photo** 



# NTEK 北测<sup>®</sup>

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